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Sheet 1 of 1

(Rev. 5/92) Comparable to Form PTO-1449  INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)	U.S. Department of Commerce Patent and Trademark Office	Atty. Docket No.  82821	Serial No.  09/856,212
	Applicant NAKAMURA et al.		
	Filing Date May 18, 2001	Group 1765	

## U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
MS	4,437,922	03/20/1984	Bischoff et al.	—	—	—
MS	4,944,834	07/31/1990	Tada et al.	—	—	—
MS	6,036,776	03/14/2000	Kotooka et al.	—	—	—

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	Document Number	Date	Name of Patentee	Class	Subclass	Translation	
						Yes	No
MS	EP 0823497	02/11/1998	MEMC Electronic Materials, Inc.	—	—	X	
MS	EP 0866150	09/23/1998	Wacker Siltronic Gesellschaft fur	—	—	X	
	EP 0785298	06/26/2002	MEMC Electronic Materials, Inc.	—	—	X	
	JP 03-279290	12/10/1991	Osaka Titanium Co., Ltd.	—	—	X	
	JP 05-194076	08/03/1993	Komatsu Denshi Kinzoku KK	—	—	X	
	JP 07-133187	05/23/1995	Komatsu Electron Metals Co., Ltd.	—	—	X	
	WO 98/45507	10/15/1998	MEMC Electronic Materials, Inc.	—	—	X	
MS	WO 98/45508	10/15/1998	MEMC Electronic Materials, Inc.	—	—	X	

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

MS	NAKAMURA, KOZO et al.: "Formation process of grown-in defects in Czochralski grown silicon crystals" JOURNAL OF CRYSTAL GROWTH 180 (1997) 61-72
MS	AMMON, WILFRIED VON et al.: "The dependence of bulk defects on the axial temperature gradient of silicon crystals during Czochralski growth" 2300 JOURNAL OF CRYSTAL GROWTH 151 (1995) June 1, Nos. 3/4, Amsterdam, NL, Pages 273-277

Examiner /Matthew Song/ <i>Matthew Song</i>	Date Considered 08/09/2006 9/27/2006
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